

DATA SHEET

SURFACE MOUNT MULTILAYER CERAMIC CAPACITORS

Automotive grade with Soft Termination

X7R

16 V to 250 V

I nF to 4.7 uF

RoHS compliant & Halogento Free



YAGEO



16 V to 250 V

SCOPE

This specification describes Automotive grade X7R series chip capacitors with flexible leadfree terminations and used for automotive equipments.

<u>APPLICATIONS</u>

All general purpose applications Entertainment applications Comfort / security applications Information applications

FEATURES

- · AEC-Q200 qualified
- MSL class: MSL I
- · Soldering is compliant with J-STD-020D
- · Increased mechanical performance
- · High component and equipment reliability
- The capacitors are 100% performed by automatic optical inspection prior to taping.

ORDERING INFORMATION - GLOBAL PART NUMBER

All part numbers are identified by the series, size, tolerance, TC material, packing style, voltage, process code, termination and capacitance value.

GLOBAL PART NUMBER

AS <u>xxxx x x xxx x</u> B <u>x xxx</u>

(2) (3) (4) (5)

(I) SIZE – INCH BASED (METRIC)

0603 (1608) / 0805 (2012) / 1206 (3216)/ 1210 (3225)

(2) TOLERANCE

 $J = \pm 5\%$

 $K = \pm 10\%$

 $M = \pm 20\%$

(3) PACKING STYLE

R = Paper/PE taping reel; Reel 7 inch

K = Blister taping reel; Reel 7 inch

P = Paper/PE taping reel; Reel 13 inch

F = Blister taping reel; Reel 13 inch

(4) TC MATERIAL

X7R

(5) RATED VOLTAGE

7 = 16 V

8 = 25 V

9 = 50 V

0 = 100 V

A = 200 V

Y = 250 V

(6) PROCESS

B = Class 2 MLCC

(7) CAPACITANCE VALUE

2 significant digits + number of zeros

The 3rd digit signifies the multiplying factor, and letter R is decimal point

Example: $121 = 12 \times 10^{1} = 120 \text{ pF}$



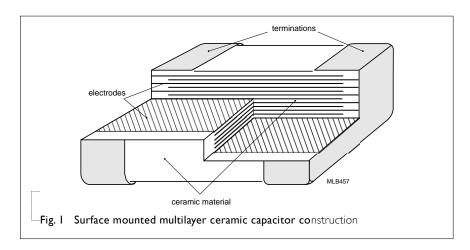
16 V to 250 V

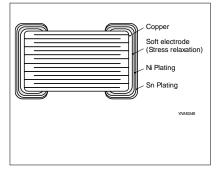
CONSTRUCTION

The capacitor consists of a rectangular block of ceramic dielectric in which a number of interleaved metal electrodes are contained. This structure gives rise to a high capacitance per unit volume.

The inner electrodes are connected to the two end flexible terminations and finally covered with a layer of plated tin (NiSn).

The terminations are lead-free. A cross section of the structure is shown in Fig.1 and Fig.2.



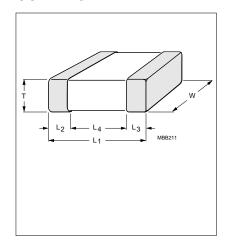


DIMENSION

Table I For outlines see fig. 3

TYPE	LI (mm)	W (mm)	T (mm)	L2/L3(mm) min	L2/L3(mm) max	L4(mm) min	
0603	1.6 ± 0.2	0.8 ± 0.15	0.8 ± 0.15	0.20	0.65	0.50	
0805	2.0 + 0.3	1.25 + 0.2	0.85 ± 0.15	- 0.25	0.75	0.70	
	2.0 ± 0.5	1.23 ± 0.2	1.25 ± 0.20	0.23	0.75		
			0.85 ± 0.15				
1206	3.2 ± 0.4	1.6 ± 0.2	1.25 ± 0.20	0.25	0.85	1.50	
			1.60 ± 0.20	-			
1210	3.2 ± 0.5	2.5 ± 0.3	2.5 ± 0.3	0.25	1.00	1.20	

OUTLINES







X7R

16 V to 250 V

CAPACITANCE RANGE & THICKNESS FOR X7R

Table 2 Size	0805						
CAP.	0603				0805		
	16 V	25 V	50 V	100 V	25 V	50 V	100 V
I.O nF	0.8±0.15	0.8±0.15	0.8±0.15	0.8±0.15	0.85±0.15	0.85±0.15	0.85±0.15
I.5 nF	0.8±0.15	0.8±0.15	0.8±0.15	0.8±0.15	0.85±0.15	0.85±0.15	0.85±0.15
2.2 nF	0.8±0.15	0.8±0.15	0.8±0.15	0.8±0.15	0.85±0.15	0.85±0.15	0.85±0.15
3.3 nF	0.8±0.15	0.8±0.15	0.8±0.15	0.8±0.15	0.85±0.15	0.85±0.15	0.85±0.15
4.7 nF	0.8±0.15	0.8±0.15	0.8±0.15	0.8±0.15	0.85±0.15	0.85±0.15	0.85±0.15
6.8 nF	0.8±0.15	0.8±0.15	0.8±0.15	0.8±0.15	0.85±0.15	0.85±0.15	0.85±0.15
IO nF	0.8±0.15	0.8±0.15	0.8±0.15	0.8±0.15	0.85±0.15	0.85±0.15	0.85±0.15
15 nF	0.8±0.15	0.8±0.15	0.8±0.15	0.8±0.15	0.85±0.15	0.85±0.15	0.85±0.15
22 nF	0.8±0.15	0.8±0.15	0.8±0.15	0.8±0.15	0.85±0.15	0.85±0.15	0.85±0.15
33 nF	0.8±0.15	0.8±0.15	0.8±0.15	0.8±0.15	0.85±0.15	0.85±0.15	1.25±0.2
47 nF	0.8±0.15	0.8±0.15	0.8±0.15	0.8±0.15	0.85±0.15	0.85±0.15	1.25±0.2
68 nF	0.8±0.15	0.8±0.15	0.8±0.15		1.25±0.2	1.25±0.2	1.25±0.2
100 nF	0.8±0.15	0.8±0.15	0.8±0.15		1.25±0.2	1.25±0.2	1.25±0.2
I uF					1.25±0.2		

NOTE

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Values in shaded cells indicate thickness class in mm



5	
15	

X7R

16 V to 250 V

CAPACITANCE RANGE & THICKNESS FOR X7R

Table 3	Size 1206								
CAP.	1206					1210			
	16V	25V	50 V	100 V	200 V / 250 V	50V	100V	200 V	250 V
22 nF					1.25±0.2			_	
33 nF					1.25±0.2				
47 nF					1.25±0.2				
68 nF					1.25±0.2				
100 nF		0.85±0.15	0.85±0.15	1.25±0.2	1.6±0.2		1.25±0.2	1.25±0.2	1.25±0.2
150 nF		1.25±0.2	1.25±0.2	1.25±0.2			1.25±0.2	1.25±0.2	1.25±0.2
220 nF	1.25±0.2	1.25±0.2	1.25±0.2	1.25±0.2			1.25±0.2	1.25±0.2	1.25±0.2
4.7 uF						2.5±0.3			

NOTE

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Values in shaded cells indicate thickness class in mm







X7R

16 V to 250 V

THICKNESS CLASSES AND PACKING QUANTITY

Table 5

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SIZE	THICKNESS	TAPE WIDTH -	Ø180	MM / 7 INCH	Ø330 I	MM / 13 INCH
CODE	CLASSIFICATION	QUANTITY PER REEL	Paper	Blister	Paper	Blister
0603	0.8 ±0.15 mm	8 mm	4,000		15,000	
0805	0.85 ±0.15 mm	8 mm	4,000		15,000	
0803	1.25 ±0.2 mm	8 mm		3,000		10,000
	0.6 ±0.1 mm	8 mm	4,000		20,000	
1206	0.85 ±0.1 mm	8 mm	4,000		15,000	
1206	1.25 ±0.2 mm	8 mm		3,000		10,000
	1.6 ±0.2 mm	8 mm		2,000		10,000
1210	2.5 ±0.3 mm	8 mm		1,000		





16 V to 250 V

ELECTRICAL CHARACTERISTICS

NP0/X7R DIELECTRIC CAPACITORS; NI/SIN TERMINATIONS

Unless otherwise specified, all test and measurements shall be made under standard atmospheric conditions for testing as given in 5.3 of IEC 60068-1:

- Temperature: 15 °C to 35 °C - Relative humidity: 25% to 75% - Air pressure: 86 kPa to 106 kPa

Before the measurements are made, the capacitor shall be stored at the measuring temperature for a time sufficient to allow the entire capacitor to reach this temperature.

The period as prescribed for recovery at the end of a test is normally sufficient for this purpose.

Table 6						
DESCRIPTIO	N					VALUE
Capacitance i	range				Li	nF to 4.7 uF
Capacitance 1	tolerance					_
X7R					±5% ^(I) , ±	10%, ±20%
Dissipation fa	actor (D.F.)					
X7R		0603	0805	1206	1210	_
	16V	InF to 100nF		220nF		≤ 3.5%
	25V	InF to 39nF	InF to 100nF	100nF to 220nF		≤ 2.5%
		47nF to 100nF				≤ 3.5%
			IμF			≤ 5%
	50V	InF to 39nF	InF to 100nF	100nF to 220nF		≤ 2.5%
		47nF to 100nF				≤ 3.5%
					4.7 uF	≤ 10%
	100V	InF to 10nF	InF to 100nF	100nF to 220nF		≤ 2.5%
		12nF to 47nF				≤ 5%
	200V / 250V			22nF to 100nF		≤ 2.5%
Insulation res	sistance after I (DC)			IR ≥ I0 GΩ or I.R ×	$C \ge 500\Omega$.F which	hever is less
function of te	pacitance change as emperature e characteristic/coef					1150/
-						±15%
Operating ter	mperature range:				_55 °C ·	to +125 °C
					55 C	

NOTE

1. Capacitance tolerance ±5% doesn't available for X7R full product range, please contact local sales force before order





16 V to 250 V

SOLDERING RECOMMENDATION

Table 7

SOLDERING	SIZE				
METHOD	0402	0603	0805	1206	≥ 1210
Reflow	≥ 0.1 µF	≥ 1.0 µF	≥ 2.2 µF	≥ 4.7 µF	Reflow only
Reflow/Wave	< 0.1 µF	< 1.0 µF	< 2.2 µF	< 4.7 µF	

SOLDERING CONDITIONS

The lead free MLCCs are able to stand the reflow soldering conditions as below:

- Temperature: above 220 °C
- Endurance: 95 to 120 seconds
- Cycles: 3 times

The test of "soldering heat resistance" is carried out in accordance with the schedule of "MIL-STD-202G-method 210F", "The robust construction of chip capacitors allows them to be completely immersed in a solder bath of 260 °C for 10 seconds". Therefore, it is possible to mount MLCCs on one side of a PCB and other discrete components on the reverse (mixed PCBs). Surface Mount Capacitors are tested for solderability at 245 $^{\circ}\text{C}$ during 2 seconds. The test condition for no leaching is 260 $^{\circ}\text{C}$ for 30 seconds.

TESTS AND REQUIREMENTS

Table 8 Test procedures and requirements

TEST	TEST METH	HOD	PROCEDURE	REQUIREMENTS
Mounting	IEC 60384- 21/22	4.3	The capacitors may be mounted on printed-circuit boards or ceramic substrates	No visible damage
Capacitance	IEC 60384- 21/22	4.5.1	At 20°C, 24 hours after annealing f = 1 KHz, measuring at voltage 1 V _{rms} at 20°C	Within specified tolerance
Dissipation Factor (D.F.)	IEC 60384- 21/22	4.5.2	At 20 °C, 24 hours after annealing f = 1 KHz, measuring at voltage 1 V _{rms} at 20°C	In accordance with specification
Insulation Resistance	IEC 60384- 21/22	4.5.3	At U_r (DC) for I minute	In accordance with specification





X7R

16 V to 250 V

TEST	TEST METH	HOD	PROCEDURE	REQUIREMENTS
High Temperature Exposure	AEC-Q200	3	Unpowered ; 1000hours @ T=150°C Measurement at 24±2 hours after test conclusion.	No visual damage ΔC/C: X7R: ±10% D.F.: within initial specified value IR: within initial specified value
Temperature Cycling	AEC-Q200	4	Preconditioning; 150 +0/-10°C for I hour, then keep for 24 ±1 hours at room temperature 1000 cycles with following detail: 30 minutes at lower category temperature 30 minutes at upper category temperature Recovery time 24 ±2 hours	No visual damage ΔC/C X7R: ±10% D.F. meet initial specified value IR meet initial specified value
Destructive Physical Analysis	AEC-Q200	5	Note: Only applies to SMD ceramics. Electrical test not required.	
Moisture Resistance	AEC-Q200	6	T=24 hrs/per cycle; 10 continuous cycles unpowered. Measurement at 24 ±2 hours after test condition.	No visual damage ΔC/C X7R: ±10% D.F. Within initial specified value IR X7R: Meet initial specified value value

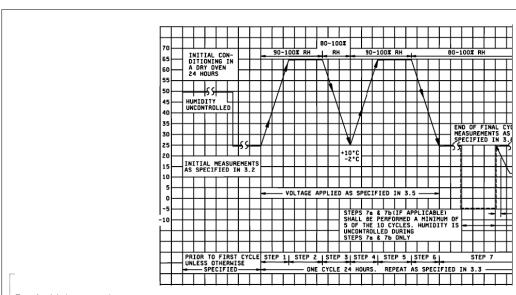


Fig. 4 Moisture resistant



TEST	TEST METH	HOD	PROCEDURE	REQUIREMENTS
Biased Humidity	AEC-Q200	7	I. Preconditioning, class 2 only: 150 +0/-10 °C /I hour, then keep for 24 ±I hour at room temp	No visual damage after recovery
			2. Initial measure: Parameter: Cap, D.F., I.R. Measuring voltage: I.5V \pm 0.1 VDC Note: Series with 100 K Ω	Δ C/C X7R: ±15% D.F. Less than 200% of initial spec.
			3. Test condition: 85 °C, 85% R.H. connected with 100 K Ω resistor, applied 1.5V/Ur for 1,000 hours.	I.R. The insulation resistance shall greater than 10% of initial spec.
			4. Recovery: Class2: 24 ±2 hours	greater than 10% of illitial spec.
			5. Final measure: Cap, D.F., I.R.	
Operational Life	AEC-Q200	8	 Preconditioning, class 2 only: 150 +0/-10 °C /I hour, then keep for 	No visual damage
			24 ± 1 hour at room temp 2. Initial measure:	ΔC/C X7R: ±15%
			Spec: refer to initial spec C, D, IR 3. Endurance test:	D.F.
			Temperature: X7R: 125 °C Specified stress voltage applied for 1,000 hours: Applied 2.0 \times U _r for general products Applied 1.5 \times U _r for high cap. Products	Less than 200% of initial spec. IR The insulation resistance shall
			High voltage series follows with below stress condition:	be greater than 10% of initial spec.
			Applied 1.5 \times Ur for 200V, 250V series	
			4. Recovery time: 24 ±2 hours	
			5. Final measure: C, D, IR	
			Note: If the capacitance value is less than the minimum value permitted, then after the other measurements have been made the capacitor shall be preconditioned according to "IEC 60384 4.1" and then the requirement shall be met.	
External Visual	AEC-Q200	9	Any applicable method using × 10 magnification	In accordance with specification
Physical Dimension	AEC-Q200	10	Verify physical dimensions to the applicable device specification.	In accordance with specification
Mechanical Shock	AEC-Q200	13	Three shocks in each direction shall be applied along the three mutually perpendicular axes of the test specimen (18 shocks) Peak value: 1,500 g's	ΔC/C X7R: ±10%
			Duration: 0.5 ms	D.F.
			Velocity change: 15.4 ft/s Waveform: Half-sin	Within initial specified value IR
				Within initial specified value





X7R

16 V to 250 V

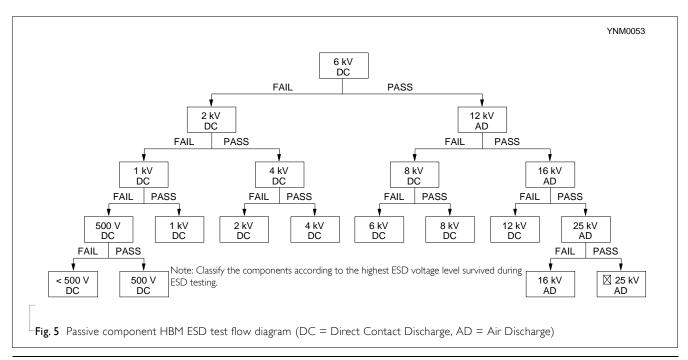
TEST	TEST METHOD		PROCEDURE	REQUIREMENTS	
Vibration	AEC-Q200 14		5 g's for 20 minutes, 12 cycles each of 3 orientations. Note:	ΔC/C X7R: ±10%	
			Use 8" x 5" PCB. 0.31" thick 7 secure points on one long side and 2 secure points at corners of opposite sides. Parts mounted within 2" from any secure point. Test from 10-2000 Hz.	D.F: meet initial specified value IR meet initial specified value	
Resistance to Soldering Heat	AEC-Q200	15	Precondition: $150 + 0/-10$ °C for I hour, then keep for 24 ± 1 hours at room temperature Preheating: for size ≤ 1206 : 120 °C to 150 °C for I minute Preheating: for size ≥ 1206 : 100 °C to 120 °C for I minute	Dissolution of the end face plating shall not exceed 25% of the length of the edge concerned	
			and 170 °C to 200 °C for I minute Solder bath temperature: 260 ±5 °C	ΔC/C Class2:	
			Dipping time: 10 ±0.5 seconds	X7R: ±10%	
			Recovery time: 24 ±2 hours	D.F. within initial specified value	
				IR within initial specified value	
Thermal Shock	AEC-Q200	16	1. Preconditioning, class 2 only: 150 +0/-10 $^{\circ}$ C /1 hour, then keep for 24 \pm 1 hour at room .	No visual damage	
			temp	ΔC/C	
			2. Initial measure:	X7R: ±15%	
			Spec: refer to initial spec C, D, IR		
			3. Rapid change of temperature test:		
			-55 °C to +125 °C; 300 cycles 15 minutes at lower category temperature; 15 minutes at upper category temperature.	D.F: meet initial specified value IR meet initial specified value	
			4. Recovery time:		
			Class 2: 24 ±2 hours		
			5. Final measure: C, D, IR		



X7R

16 V to 250 V

PROCEDURE REQUIREMENTS TEST TEST METHOD ESD A component passes a voltage AEC-Q200 Per AEC-Q200-004 level if all components stressed at that voltage level pass.



Solderability

AEC-Q200

18

1. Preheat at 155°C for 4 hours. After preheating, immerse the capacitor in a solution of ethanol and rosin (25% rosin

in weight proportion). Immerse in eutectic solder solution for 5+0/-0.5 seconds at 235±5°C.

- 2. Should be placed into steam aging for 8 hours±15 minutes. After preheating, immerse the capacitor in a solution of ethanol and rosin (25% rosin in weight proportion). Immerse in eutectic solder solution for 5+0/-0.5 seconds at 235±5°C.
- 3. Should be placed into steam aging for 8 hours±15 minutes. After preheating, immerse the capacitor in a solution of Ethanol and rosin (25% rosin in weight proportion). Immerse in eutectic solder solution for 120±5 seconds at 260±5°C.

The solder should cover over 95% of the critical area of each termination.

Electrical Characterization

AEC-Q200

19

Parametrically test per lot and sample size requirements, summary to show Min, Max, Mean and Standard deviation at room as well as Min and Max operating temperatures.

 Δ C/C Class2: X7R: ±15%

X7R: -55 °C to +125 °C Normal temperature: 20 °C



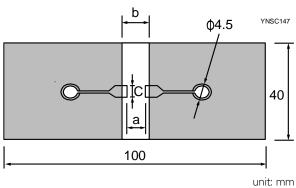


X7R

16 V to 250 V

PROCEDURE TEST **TEST METHOD REQUIREMENTS Board Flex** Part mounted on a 100 mm X 40 mm FR4 PCB board, which AEC-Q200 No visible damage is 1.6 ± 0.2 mm thick and has a layer-thickness 35 μm \pm 10 Δ C/C μm. Class2: Part should be mounted using the following soldering reflow X7R: ±10% profile. Conditions: Class2: Bending 5 mm at a rate of 1 mm/s, radius jig 230 mm

Test Substrate:



	Dimen	sion(m	m)
Туре	а	b	С
0201	0.3	0.9	0.3
0402	0.4	1.5	0.5
0603	1.0	3.0	1.2
0805	1.2	4.0	1.65
1206	2.2	5.0	1.65
1210	2.2	5.0	2.0
1808	3.5	7.0	3.7
	•		•

Terminal Strength	AEC-Q200	22	With the component mounted on a PCB obtained with the device to be tested, apply a 17.7N (1.8Kg) force to the side of a device being tested. This force shall be applied for 60+1 seconds. Also the force shall be applied gradually as not to apply a shock to the component being tested. * Apply 2N force for 0402 size.	Magnification of 20X or greater may be employed for inspection of the mechanical integrity of the device body, terminals and body/terminal junction. Before and after the test, the device shall comply with all electrical requirements stated in this specification.
Beam Load Test	AEC-Q200	23	Place the part in the beam load fixture. Apply a force until the part breaks or the minimum acceptable force level required in the user specification(s) is attained.	≤ 0805 Thickness > 0.5 mm: 20N Thickness ≤ 0.5 mm: 8N ≥ 1206 Thickness ≥1.25 mm: 54N Thickness < 1.25 mm: 15N
Voltage Proof	IEC 60384-1	4.6	Specified stress voltage applied for $I \sim 5$ seconds Ur ≤ 100 V: series applied 2.5 Ur $I00$ V ≤ 100 V series applied (1.5 Ur + 100) $I00$ V $I00$ V series applied (1.3 Ur + 100) Charge/Discharge current is less than 50mA	







16 V to 250 V

REVISION HISTORY

YAGEO

REVISION	DATE	CHANGE NOTIFICATION	DESCRIPTION
Version 3	Nov. 28, 2022	-	- Update Biased Humidity and operation life requirements.
Version 2	Dec. 21, 2020	-	- Add X7R product range, 0603, InF to I5nF, I6 to I00V
Version I	Dec. 04, 2018	-	- Add 0603/ 22nF to 100nF
Version 0	Oct. 05, 2017	-	- New





Surface-Mount Ceramic Multilayer Capacitors

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